

**Information-Analytical System Assessment
and Forecasting of Metrological Reliability
of Electronic Measuring Devices**

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Abstract: The paper describes the main stages of operation of information-analytical system assessment and forecasting of metrological reliability of electronic measuring devices. Information-analytical system selects an optimal mathematical description of the time variation of a number of metrological characteristics and, thus, gives the solution of metrological reliability assessment at the stage of the forthcoming EIS operation. The developed information-analytical system selects the values of calibration intervals, calculates the required number of measurements during verifications electronic measuring devices. Information-analytical system enables time-efficient assessment of the metrological characteristics and metrological reliability of the projected electronic measuring devices.

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